

Search Notes**Application/Control No.**

10/723,948

Examiner

Y. J. Han

Applicant(s)/Patent under Reexamination

STANESCU ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
323	293		
	297		
	298		
	352		
	353		
	354		
377	52		
327	519		
	594		
341	142		
365	185.05		
	185.08		
713	300		
338	13	3/05	GR

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner